

CLAIMS

I claim:

1. A system for incremental statistical timing analysis of an electrical circuit
5 comprising:
 - a. a results input for receiving one or more results of a first statistical timing analysis;
 - b. a change input for receiving one or more changes to the electrical circuit;
 - c. a query input for receiving one or more statistical timing queries that request updated statistical timing information about the electrical circuit;
10 and
 - d. an incremental statistical timing process that provides the one or more answers to the respective queries as an output of the system, the answer being the requested statistical timing information for the electrical circuit
15 with the changes.
2. A system, as in claim 1, where the query is one or more of: a statistical arrival time at a node, a statistical required arrival time at a node, a statistical slack at a node, a statistical slew at a node, an arrival tightness probability of an edge, a required arrival tightness probability of an edge, a criticality probability of an edge, a criticality probability of a node, and a probability of a timing test being met.
20

3. A system, as in claim 2, where the query requests one or more of the following: a mean, a variance, an independent random part, a sensitivity to a source of variation, a confidence level, and an entire probability distribution of a statistical timing quantity.

5

4. A system, as in claim 1, where the query requests a criticality of one or more paths through the electrical circuit.

5. A system, as in claim 1, where the query requests a listing of one or more paths through the electrical circuit with the highest probability of being critical.

10

6. A system, as in claim 1, where the query requests a listing of a required number of paths through the electrical circuit in order of criticality probability.

15

7. A system, as in claim 1, where the query requests a listing of one or more critical paths through the electrical circuit in order of criticality probability until the sum of the criticality probabilities exceeds a required probability threshold.

8. A system, as in claim 2, where the query requests one or more of: a late mode statistical timing quantity, an early mode statistical timing quantity, a rising statistical timing quantity, and a falling statistical timing quantity.

20

9. A system, as in claim 1, where the change is one or more of: a removal of a wire, an addition of a wire, a buffering of a wire, a removal of a gate, an addition of a gate, a removal of a latch, an addition of a latch, a removal of a clock phase, an addition of a clock phase, and a change in the operating conditions under which timing is performed.

10. A system, as in claim 9, in which a change to the electrical circuit is the undoing of the previous change to the electrical circuit.

10 11. A system, as in claim 1, where the electrical circuit is one of a combinational circuit and a sequential circuit.

12. A system, as in claim 1, where the electrical circuit contains one or more of: a master-slave latch, a transparent latch, a dynamic circuit, and a flip-flop.

15 13. A system, as in claim 1, where the electrical circuit has multiple clock phases.

14. A system, as in claim 1, where a delay of each of one or more components of the electrical circuit is modeled as the sum of one or more of a constant part, a correlated random part, and an independent random part.

15. A system, as in claim 14, where the correlated random part of the delay of each component is a function of one or more common sources of variation.

16. A system, as in claim 1, where a first statistical timing analysis propagates timing values as a weighted sum of probability distributions of one or more of the sources of variation.

17. A method for incremental statistical timing analysis, comprising the steps of:

- a. conducting an initial statistical timing analysis and saving one or more arrival tightness probabilities and one or more required arrival tightness probabilities;
- b. creating a change list based on the changes to the electrical circuit and the one or more statistical timing queries, and assigning levelization parameters;
- c. conducting incremental statistical forward propagation of the arrival times and tightness probabilities;
- d. conducting incremental statistical reverse propagation of required arrival times and required arrival tightness probabilities; and
- e. answering the one or more statistical timing queries.

18. A method, as in claim 17, where the query is one or more of: a statistical arrival time at a node, a statistical required arrival time at a node, a statistical slack at a node, a statistical slew at a node, an arrival tightness probability of an edge, a

required arrival tightness probability of an edge, a criticality probability of an edge, a criticality probability of a node, and a probability of a timing test being met.

5 19. A method, as in claim 17, where the query requests one or more of the following:
 a mean, a variance, an independent random part, a sensitivity to a source of variation, a confidence level, and an entire probability distribution of a statistical timing quantity.

10 20. A method, as in claim 17, where the query requests a criticality of one or more paths through the electrical circuit.

21. A method, as in claim 17, where the query requests a listing of the path through the electrical circuit with the highest probability of being critical.

15

22. A method, as in claim 17, where the query requests a listing of a required number of paths through the electrical circuit in order of criticality probability.

20 23. A method, as in claim 17, where the query requests a listing of critical paths through the electrical circuit in order of criticality probability until the sum of the criticality probabilities exceeds a required probability threshold.

24. A method, as in claim 17, where the query requests one or more of: a late mode statistical timing quantity, an early mode statistical timing quantity, a rising statistical timing quantity, and a falling statistical timing quantity.

5 25. A method, as in claim 17, where the change is one or more of: a removal of a wire, an addition of a wire, a buffering of a wire, a removal of a gate, an addition of a gate, a removal of a latch, an addition of a latch, a removal of a clock phase, an addition of a clock phase, and a change in the operating conditions under which timing is performed.

10

26. A method, as in claim 25, in which a change to the electrical circuit is the undoing of the previous change to the electrical circuit.

15

27. A method, as in claim 17, where the electrical circuit is one of a combinational circuit and a sequential circuit.

28. A method, as in claim 17, where the electrical circuit contains one or more of: a master-slave latch, a transparent latch, a dynamic circuit, and a flip-flop.

20 29. A method, as in claim 17, where the electrical circuit has multiple clock phases.

30. A method, as in claim 17, where the delay of each component of the electrical circuit is modeled as the sum of one or more of a constant part, a correlated

random part, and an independent random part.

31. A method, as in claim 30, where the correlated random part of the delay of each component is a function of one or more common sources of variation.

5

32. A method, as in claim 17, where a first statistical timing analysis propagates timing values as a weighted sum of probability distributions of one or more of the sources of variation.

10 33. A system for incremental statistical timing analysis, comprising:

- a. means for conducting an initial statistical timing analysis and saving one or more arrival tightness and one or more required arrival tightness probabilities;
- b. means for creating a change list based on the changes to the electrical circuit and the one or more statistical timing queries, and assigning levelization parameters;
- c. means for conducting incremental statistical forward propagation of the arrival times and arrival tightness probabilities;
- d. means for conducting incremental statistical reverse propagation of required arrival times and required arrival tightness probabilities; and
- e. means for answering the one or more statistical timing queries.

15

20

34. A computer memory storing a method for incremental statistical timing analysis,

the method comprising the steps of:

- a. conducting an initial statistical timing analysis and saving one or more arrival tightness probabilities and one or more required arrival tightness probabilities;
- b. creating a change list based on the changes to the electrical circuit and the one or more statistical timing queries, and assigning levelization parameters;
- c. conducting incremental statistical forward propagation of the arrival times and tightness probabilities;
- d. conducting incremental statistical reverse propagation of required arrival times and required arrival tightness probabilities; and
- e. answering the one or more statistical timing queries.

15 35. A product output response to a query produced by a process for incremental

statistical timing analysis, the process comprising the steps of:

- a. conducting an initial statistical timing analysis and saving one or more arrival tightness probabilities and one or more required arrival tightness probabilities;
- b. creating a change list based on the changes to the electrical circuit and the one or more statistical timing queries, and assigning levelization parameters;

- c. conducting incremental statistical forward propagation of the arrival times and tightness probabilities;
- d. conducting incremental statistical reverse propagation of required arrival times and required arriveal tightness probabilities; and
- 5 e. providing the output response by answering the one or more statistical timing queries.